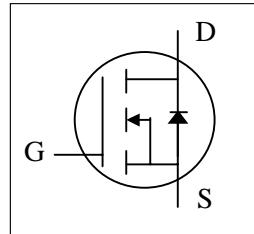
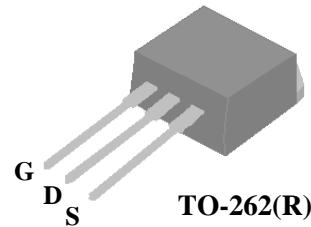


- ▼ 100% R_g & UIS Test
- ▼ Simple Drive Requirement
- ▼ Low On-resistance
- ▼ RoHS Compliant & Halogen-Free



BV_{DSS}	60V
$R_{DS(ON)}$	3.5mΩ



Description

XP6NA3R5 series are innovated design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TO-262 package is widely preferred for commercial-industrial through-hole applications and suited for low voltage applications such as DC/DC converters.

Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	105	A
$I_D @ T_C = 100^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	66	A
I_{DM}	Pulsed Drain Current ¹	360	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation	69.4	W
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation	2	W
E_{AS}	Single Pulse Avalanche Energy ³	173	mJ
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Maximum Thermal Resistance, Junction-case	1.8	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient	62	°C/W

Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	60	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=40\text{A}$	-	-	3.5	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=250\mu\text{A}$	2	-	4	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_D=40\text{A}$	-	90	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=48\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	25	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 0.1	uA
Q_g	Total Gate Charge ⁴	$I_D=40\text{A}$	-	62	99	nC
Q_{gs}	Gate-Source Charge ⁴	$V_{\text{DS}}=30\text{V}$	-	18	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge ⁴	$V_{\text{GS}}=10\text{V}$	-	17	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ⁴	$V_{\text{DS}}=30\text{V}$	-	17	-	ns
t_r	Rise Time ⁴	$I_D=40\text{A}$	-	73	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time ⁴	$R_G=6\Omega$	-	40	-	ns
t_f	Fall Time ⁴	$V_{\text{GS}}=10\text{V}$	-	90	-	ns
C_{iss}	Input Capacitance ⁴	$V_{\text{GS}}=0\text{V}$	-	3400	5440	pF
C_{oss}	Output Capacitance ⁴	$V_{\text{DS}}=50\text{V}$	-	560	-	pF
C_{rss}	Reverse Transfer Capacitance ⁴	f=1.0MHz	-	30	-	pF
R_g	Gate Resistance	f=1.0MHz	-	1	2	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=40\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
t_{rr}	Reverse Recovery Time ⁴	$I_S=40\text{A}$, $V_{\text{GS}}=0\text{V}$	-	40	-	ns
Q_{rr}	Reverse Recovery Charge ⁴	dl/dt=100A/ μs	-	35	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Starting $T_j=25^\circ\text{C}$, $V_{\text{DD}}=30\text{V}$, $L=0.3\text{mH}$, $R_G=25\Omega$, $V_{\text{GS}}=10\text{V}$
- 4.Guaranteed by design.
- 5.These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT, AUTOMOTIVE OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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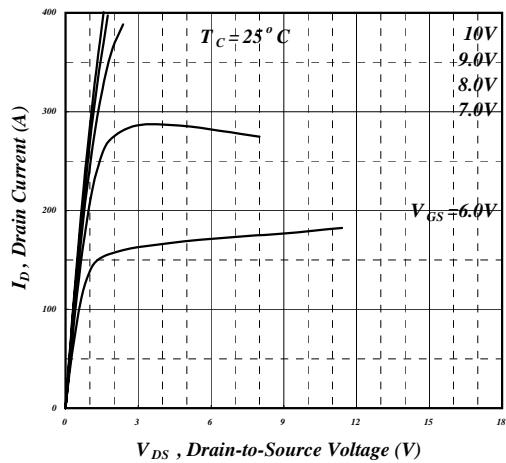


Fig 1. Typical Output Characteristics

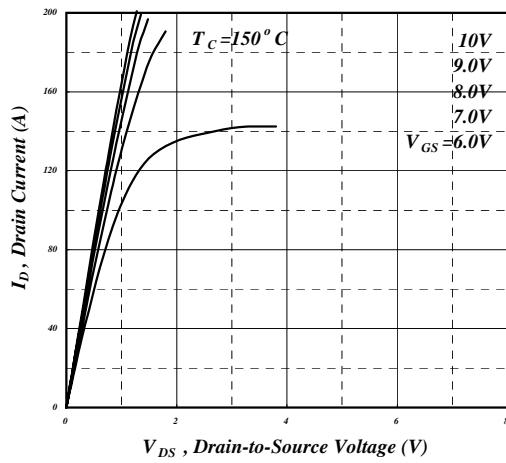


Fig 2. Typical Output Characteristics

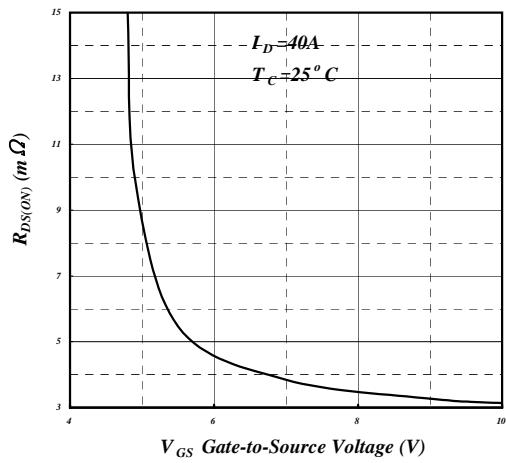


Fig 3. On-Resistance v.s. Gate Voltage

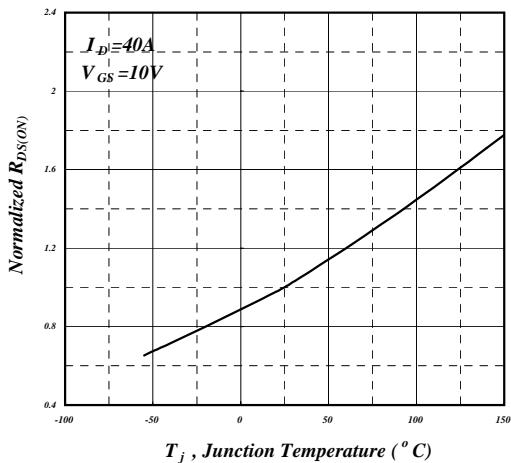


Fig 4. Normalized On-Resistance v.s. Junction Temperature

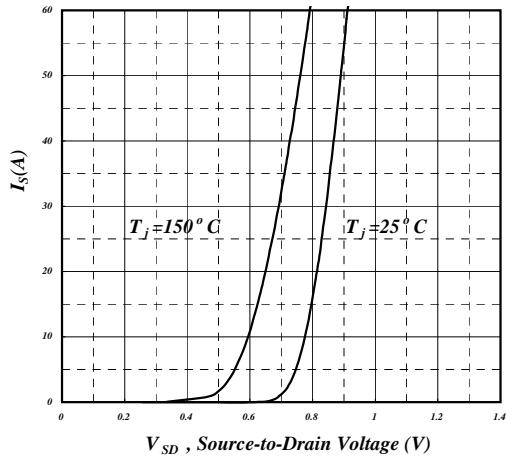


Fig 5. Forward Characteristic of Reverse Diode

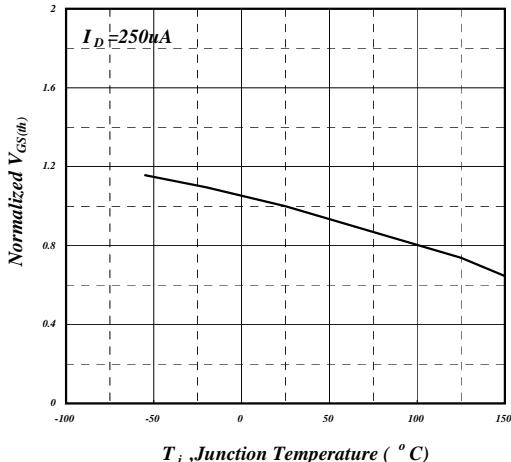


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

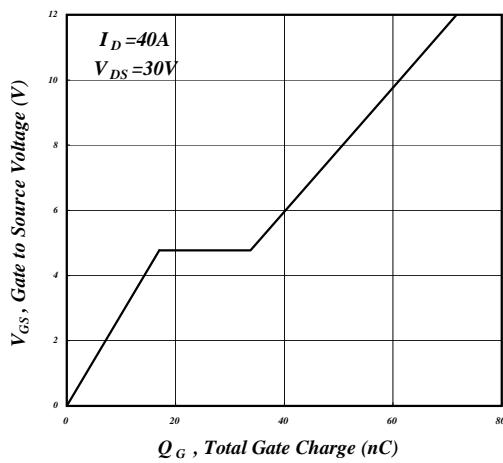


Fig 7. Gate Charge Characteristics

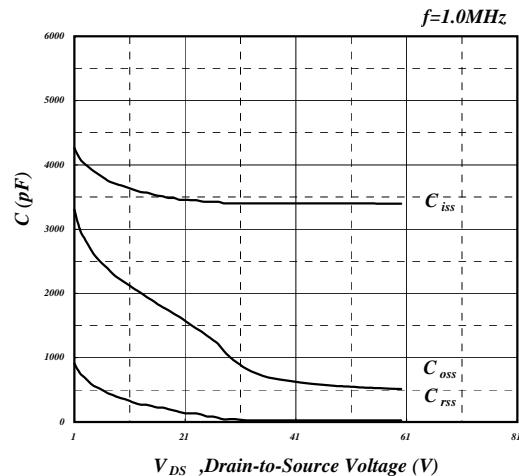


Fig 8. Typical Capacitance Characteristics

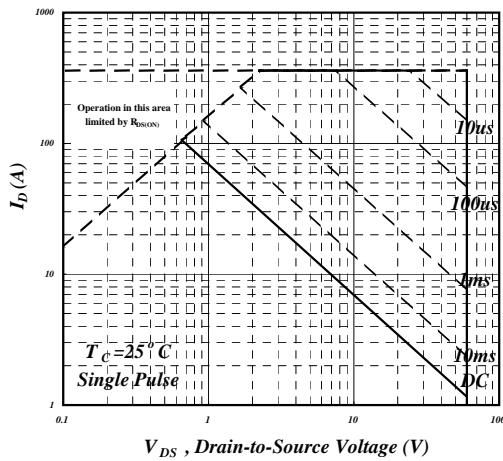


Fig 9. Maximum Safe Operating Area⁵

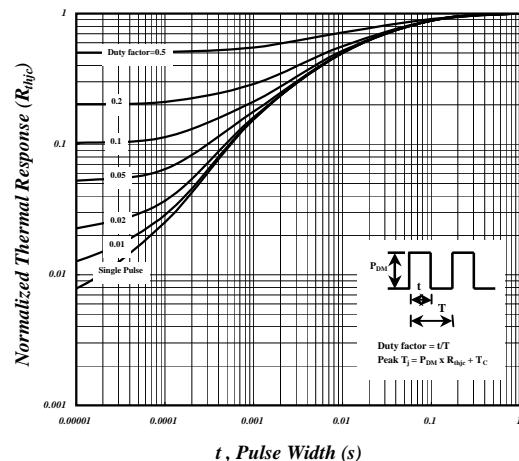


Fig 10. Effective Transient Thermal Impedance

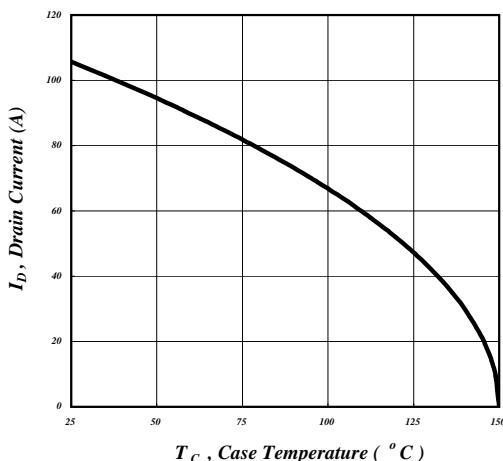


Fig 11. Drain Current v.s. Case Temperature

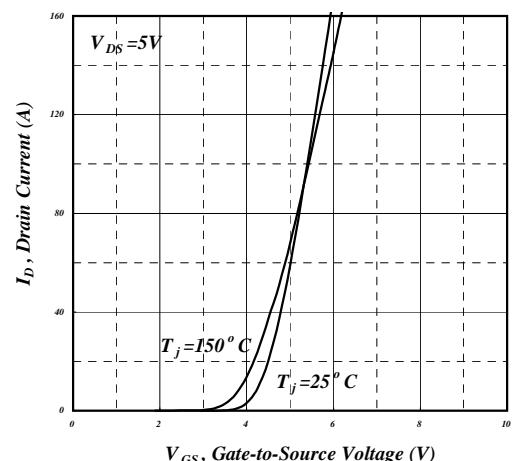


Fig 12. Transfer Characteristics

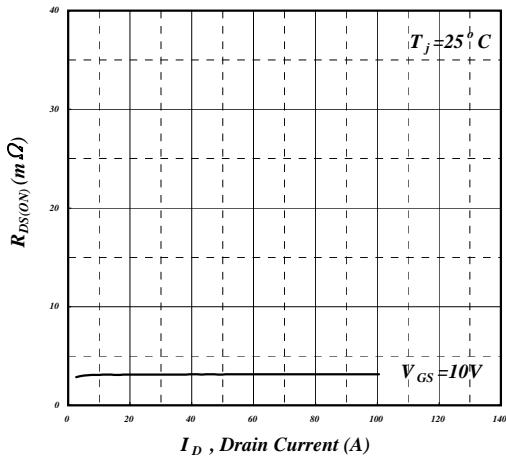


Fig 13. Typ. Drain-Source on State Resistance

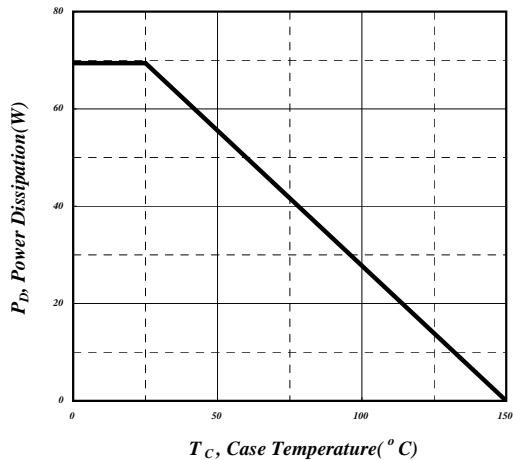


Fig 14. Total Power Dissipation

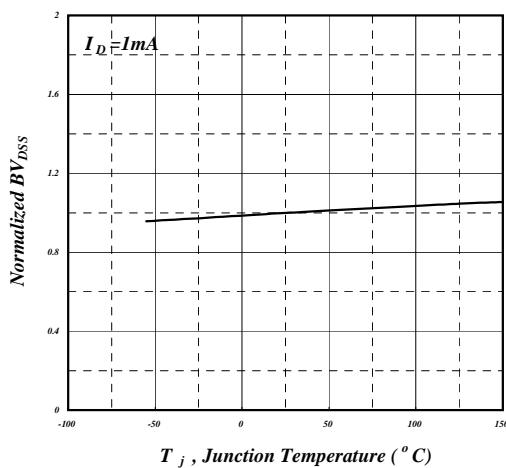
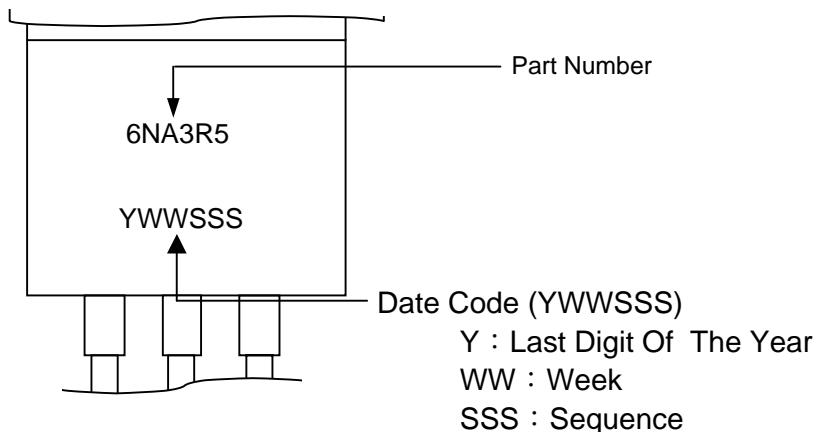
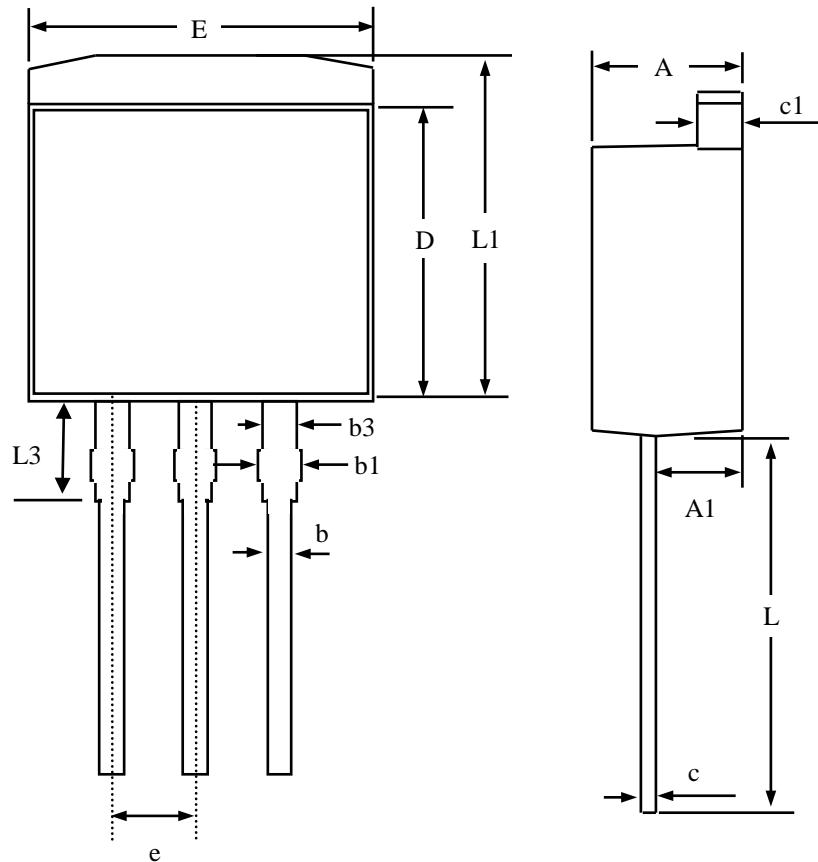


Fig 15. Normalized BV_{DSS} v.s. Junction Temperature

MARKING INFORMATION

Package Outline : TO-262



SYMBOLS	Millimeters		
	MIN	NOM	MAX
A	4.24	4.54	4.84
A1	2.10	2.50	2.90
b	0.65	0.85	1.05
b1	0.75	1.25	1.75
b3	0.75	1.23	1.70
c	0.28	0.44	0.60
c1	1.15	1.3	1.45
D	8.30	8.9	9.50
E	9.50	10	10.50
e	2.04	2.54	3.04
L	10.50	12.5	14.50
L1	8.50	10	11.50
L3	1.3 ~ 4.8 (ref)		

1. All Dimensions Are in Millimeters.

2. Dimension Does Not Include Mold Protrusions.

Draw No. M1-R3-IFET-G-v07

TO-262 FOOTPRINT :

